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Freescale Semiconductor
Technical Data

MPC8540EC
Rev. 4.1, 07/2007

MPC8540 Integrated Processor Hardware Specifications

The MPC8540 integrates a PowerPC™ processor core built on Power Architecture™ technology with system logic required for networking, telecommunications, and wireless infrastructure applications. The MPC8540 is a member of the PowerQUICC™ III family of devices that combine system-level support for industry-standard interfaces with processors that implement the embedded category of the Power Architecture technology. For functional characteristics of the processor, refer to the *MPC8540 PowerQUICC III Integrated Host Processor Reference Manual*.

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Contents

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1 Overview

The following section provides a high-level overview of the MPC8540 features. Figure 1 shows the major functional units within the MPC8540.

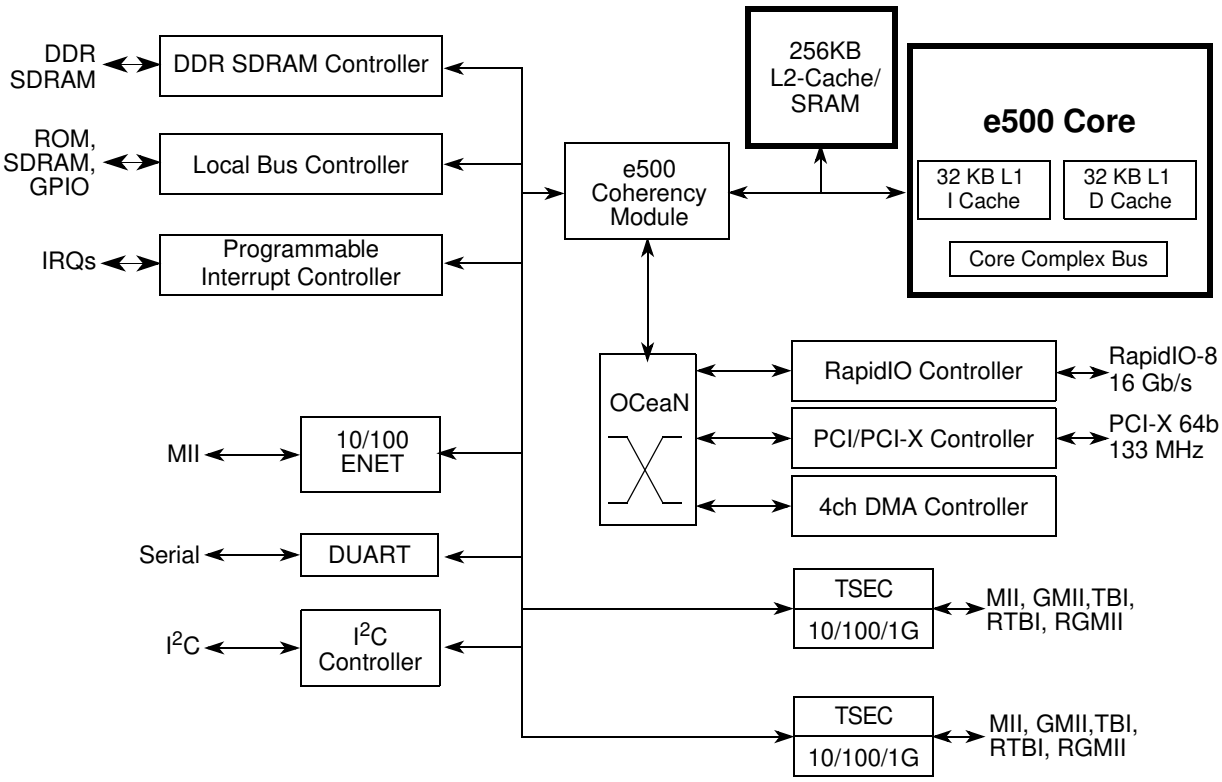


Figure 1. MPC8540 Block Diagram

1.1 Key Features

The following lists an overview of the MPC8540 feature set.

- High-performance, 32-bit Book E–enhanced core that implements the Power Architecture
  - 32-Kbyte L1 instruction cache and 32-Kbyte L1 data cache with parity protection. Caches can be locked entirely or on a per-line basis. Separate locking for instructions and data
  - Memory management unit (MMU) especially designed for embedded applications
  - Enhanced hardware and software debug support
  - Performance monitor facility (similar to but different from the MPC8540 performance monitor described in Chapter 18, “Performance Monitor.”

- 256 Kbyte L2 cache/SRAM
  - Can be configured as follows
    - Full cache mode (256-Kbyte cache).
    - Full memory-mapped SRAM mode (256-Kbyte SRAM mapped as a single 256-Kbyte block or two 128-Kbyte blocks)
    - Half SRAM and half cache mode (128-Kbyte cache and 128-Kbyte memory-mapped SRAM)
  - Full ECC support on 64-bit boundary in both cache and SRAM modes
  - Cache mode supports instruction caching, data caching, or both
  - External masters can force data to be allocated into the cache through programmed memory ranges or special transaction types (stashing)
  - Eight-way set-associative cache organization (1024 sets of 32-byte cache lines)
  - Supports locking the entire cache or selected lines. Individual line locks are set and cleared through Book E instructions or by externally mastered transactions
  - Global locking and flash clearing done through writes to L2 configuration registers
  - Instruction and data locks can be flash cleared separately
  - Read and write buffering for internal bus accesses
  - SRAM features include the following:
    - I/O devices access SRAM regions by marking transactions as snoopable (global)
    - Regions can reside at any aligned location in the memory map
    - Byte accessible ECC is protected using read-modify-write transactions accesses for smaller than cache-line accesses.
- Address translation and mapping unit (ATMU)
  - Eight local access windows define mapping within local 32-bit address space
  - Inbound and outbound ATMUs map to larger external address spaces
    - Three inbound windows plus a configuration window on PCI/PCI-X
    - Four inbound windows plus a default and configuration window on RapidIO
    - Four outbound windows plus default translation for PCI
    - Eight outbound windows plus default translation for RapidIO
- DDR memory controller
  - Programmable timing supporting DDR-1 SDRAM
  - 64-bit data interface, up to 333-MHz data rate
  - Four banks of memory supported, each up to 1 Gbyte
  - DRAM chip configurations from 64 Mbits to 1 Gbit with x8/x16 data ports
  - Full ECC support
  - Page mode support (up to 16 simultaneous open pages)
  - Contiguous or discontiguous memory mapping

  - Read-modify-write support for RapidIO atomic increment, decrement, set, and clear transactions
  - Sleep mode support for self refresh SDRAM
  - Supports auto refreshing
  - On-the-fly power management using CKE signal
  - Registered DIMM support
  - Fast memory access via JTAG port
  - 2.5-V SSTL2 compatible I/O
- RapidIO interface unit
  - 8-bit RapidIO I/O and messaging protocols
  - Source-synchronous double data rate (DDR) interfaces
  - Supports small type systems (small domain, 8-bit device ID)
  - Supports four priority levels (ordering within a level)
  - Reordering across priority levels
  - Maximum data payload of 256 bytes per packet
  - Packet pacing support at the physical layer
  - CRC protection for packets
  - Supports atomic operations increment, decrement, set, and clear
  - LVDS signaling
- RapidIO–compliant message unit
  - One inbound data message structure (inbox)
  - One outbound data message structure (outbox)
  - Supports chaining and direct modes in the outbox
  - Support of up to 16 packets per message
  - Support of up to 256 bytes per packet and up to 4 Kbytes of data per message
  - Supports one inbound doorbell message structure
- Programmable interrupt controller (PIC)
  - Programming model is compliant with the OpenPIC architecture
  - Supports 16 programmable interrupt and processor task priority levels
  - Supports 12 discrete external interrupts
  - Supports 4 message interrupts with 32-bit messages
  - Supports connection of an external interrupt controller such as the 8259 programmable interrupt controller
  - Four global high resolution timers/counters that can generate interrupts
  - Supports 22 other internal interrupt sources
  - Supports fully nested interrupt delivery
  - Interrupts can be routed to external pin for external processing

  - Interrupts can be routed to the e500 core's standard or critical interrupt inputs
  - Interrupt summary registers allow fast identification of interrupt source
- I^2C controller
  - Two-wire interface
  - Multiple master support
  - Master or slave I^2C mode support
  - On-chip digital filtering rejects spikes on the bus
- Boot sequencer
  - Optionally loads configuration data from serial ROM at reset via the I^2C interface
  - Can be used to initialize configuration registers and/or memory
  - Supports extended I^2C addressing mode
  - Data integrity checked with preamble signature and CRC
- DUART
  - Two 4-wire interfaces (SIN, SOUT, $\overline{\text{RTS}}$, $\overline{\text{CTS}}$)
  - Programming model compatible with the original 16450 UART and the PC16550D
- 10/100 fast Ethernet controller (FEC)
  - Operates at 10 to 100 megabits per second (Mbps) as a device debug and maintenance port
- Local bus controller (LBC)
  - Multiplexed 32-bit address and data operating at up to 166 MHz
  - Eight chip selects support eight external slaves
  - Up to eight-beat burst transfers
  - The 32-, 16-, and 8-bit port sizes are controlled by an on-chip memory controller
  - Three protocol engines available on a per chip select basis:
    - General purpose chip select machine (GPCM)
    - Three user programmable machines (UPMs)
    - Dedicated single data rate SDRAM controller
  - Parity support
  - Default boot ROM chip select with configurable bus width (8-,16-, or 32-bit)
- Two three-speed (10/100/1Gb) Ethernet controllers (TSECs)
  - Dual IEEE 802.3, 802.3u, 802.3x, 802.3z, 802.3ac, 802.3ab compliant controllers
  - Support for different Ethernet physical interfaces:
    - 10/100/1Gb Mbps IEEE 802.3 GMII
    - 10/100 Mbps IEEE 802.3 MII
    - 10 Mbps IEEE 802.3 MII
    - 1000 Mbps IEEE 802.3z TBI
    - 10/100/1Gb Mbps RGMII/RTBI
  - Full- and half-duplex support

  - Buffer descriptors are backward compatible with MPC8260 and MPC860T 10/100 programming models
  - 9.6-Kbyte jumbo frame support
  - RMON statistics support
  - 2-Kbyte internal transmit and receive FIFOs
  - MII management interface for control and status
  - Programmable CRC generation and checking
  - Ability to force allocation of header information and buffer descriptors into L2 cache.
- OCeaN switch fabric
  - Four-port crossbar packet switch
  - Reorders packets from a source based on priorities
  - Reorders packets to bypass blocked packets
  - Implements starvation avoidance algorithms
  - Supports packets with payloads of up to 256 bytes
- Integrated DMA controller
  - Four-channel controller
  - All channels accessible by both the local and remote masters
  - Extended DMA functions (advanced chaining and striding capability)
  - Support for scatter and gather transfers
  - Misaligned transfer capability
  - Interrupt on completed segment, link, list, and error
  - Supports transfers to or from any local memory or I/O port
  - Selectable hardware-enforced coherency (snoop/no-snoop)
  - Ability to start and flow control each DMA channel from external 3-pin interface
  - Ability to launch DMA from single write transaction
- PCI/PCI-X controller
  - PCI 2.2 and PCI-X 1.0 compatible
  - 64- or 32-bit PCI port supports at 16 to 66 MHz
  - 64-bit PCI-X support up to 133 MHz
  - Host and agent mode support
  - 64-bit dual address cycle (DAC) support
  - PCI-X supports multiple split transactions
  - Supports PCI-to-memory and memory-to-PCI streaming
  - Memory prefetching of PCI read accesses
  - Supports posting of processor-to-PCI and PCI-to-memory writes
  - PCI 3.3-V compatible
  - Selectable hardware-enforced coherency

- Power management
  - Fully static 1.2-V CMOS design with 3.3- and 2.5-V I/O
  - Supports power saving modes: doze, nap, and sleep
  - Employs dynamic power management, which automatically minimizes power consumption of blocks when they are idle.
- System performance monitor
  - Supports eight 32-bit counters that count the occurrence of selected events
  - Ability to count up to 512 counter-specific events
  - Supports 64 reference events that can be counted on any of the 8 counters
  - Supports duration and quantity threshold counting
  - Burstiness feature that permits counting of burst events with a programmable time between bursts
  - Triggering and chaining capability
  - Ability to generate an interrupt on overflow
- System access port
  - Uses JTAG interface and a TAP controller to access entire system memory map
  - Supports 32-bit accesses to configuration registers
  - Supports cache-line burst accesses to main memory
  - Supports large block (4-Kbyte) uploads and downloads
  - Supports continuous bit streaming of entire block for fast upload and download
- IEEE 1149.1-compliant, JTAG boundary scan
- 783 FC-PBGA package

2 Electrical Characteristics

This section provides the electrical specifications and thermal characteristics for the MPC8540. The MPC8540 is currently targeted to these specifications. Some of these specifications are independent of the I/O cell, but are included for a more complete reference. These are not purely I/O buffer design specifications.

2.1 Overall DC Electrical Characteristics

This section covers the ratings, conditions, and other characteristics.

2.1.1 Absolute Maximum Ratings

Table 1 provides the absolute maximum ratings.

Table 1. Absolute Maximum Ratings [1]

Characteristic		Symbol	Max Value	Unit	Notes
Core supply voltage For devices rated at 667 and 833 MHz For devices rated at 1 GHz		V_{DD}	 –0.3 to 1.32 –0.3 to 1.43	V	
PLL supply voltage For devices rated at 667 and 833 MHz For devices rated at 1 GHz		AV_{DD}	 –0.3 to 1.32 –0.3 to 1.43	V	
DDR DRAM I/O voltage		GV_{DD}	–0.3 to 3.63	V	
Three-speed Ethernet I/O voltage		LV_{DD}	–0.3 to 3.63 –0.3 to 2.75	V	
PCI/PCI-X, local bus, RapidIO, 10/100 Ethernet, MII management, DUART, system control and power management, I^2C, and JTAG I/O voltage		OV_{DD}	–0.3 to 3.63	V	3
Input voltage	DDR DRAM signals	MV_{IN}	–0.3 to (GV_{DD} + 0.3)	V	2, 5
	DDR DRAM reference	MV_{REF}	–0.3 to (GV_{DD} + 0.3)	V	2, 5
	Three-speed Ethernet signals	LV_{IN}	–0.3 to (LV_{DD} + 0.3)	V	4, 5
	Local bus, RapidIO, 10/100 Ethernet, DUART, SYSCLK, system control and power management, I^2C, and JTAG signals	OV_{IN}	–0.3 to (OV_{DD} + 0.3)	V	5
	PCI/PCI-X	OV_{IN}	–0.3 to (OV_{DD} + 0.3)	V	6
Storage temperature range		T_{STG}	–55 to 150	•C	

Notes:

1. Functional and tested operating conditions are given in Table 2. Absolute maximum ratings are stress ratings only, and functional operation at the maximums is not guaranteed. Stresses beyond those listed may affect device reliability or cause permanent damage to the device.
2. **Caution:** MV_{IN} must not exceed GV_{DD} by more than 0.3 V. This limit may be exceeded for a maximum of 20 ms during power-on reset and power-down sequences.
3. **Caution:** OV_{IN} must not exceed OV_{DD} by more than 0.3 V. This limit may be exceeded for a maximum of 20 ms during power-on reset and power-down sequences.
4. **Caution:** LV_{IN} must not exceed LV_{DD} by more than 0.3 V. This limit may be exceeded for a maximum of 20 ms during power-on reset and power-down sequences.
5. (M,L,O)V_{IN} and MV_{REF} may overshoot/undershoot to a voltage and for a maximum duration as shown in Figure 2.
6. OV_{IN} on the PCI interface may overshoot/undershoot according to the PCI Electrical Specification for 3.3-V operation, as shown in Figure 3.

2.1.2 Power Sequencing

The MPC8540 requires its power rails to be applied in a specific sequence in order to ensure proper device operation. These requirements are as follows for power up:

1. V_{DD}, AV_{DD}
2. GV_{DD}, LV_{DD}, OV_{DD} (I/O supplies)

Items on the same line have no ordering requirement with respect to one another. Items on separate lines must be ordered sequentially such that voltage rails on a previous step must reach 90 percent of their value before the voltage rails on the current step reach 10 percent of theirs.

NOTE

If the items on line 2 must precede items on line 1, please ensure that the delay will not exceed 500 ms and the power sequence is not done greater than once per day in production environment.

NOTE

From a system standpoint, if the I/O power supplies ramp prior to the V_{DD} core supply, the I/Os on the MPC8540 may drive a logic one or zero during power-up.

2.1.3 Recommended Operating Conditions

Table 2 provides the recommended operating conditions for the MPC8540. Note that the values in Table 2 are the recommended and tested operating conditions. Proper device operation outside of these conditions is not guaranteed.

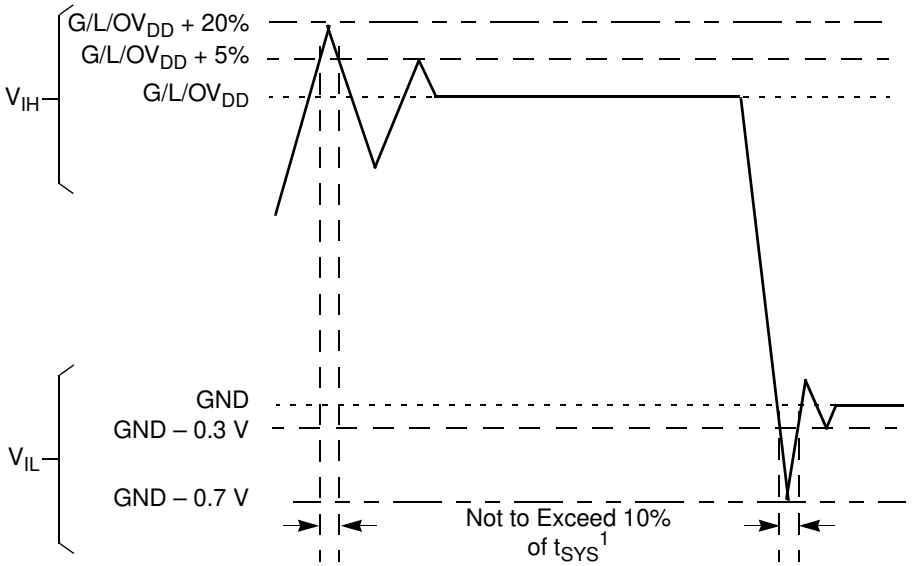
Table 2. Recommended Operating Conditions

Characteristic	Symbol	Recommended Value	Unit
Core supply voltage For devices rated at 667 and 833 MHz For devices rated at 1 GHz	V_{DD}	 1.2 V ± 60 mV 1.3 V ± 50 mV	V
PLL supply voltage For devices rated at 667 and 833 MHz For devices rated at 1 GHz	AV_{DD}	 1.2 V ± 60 mV 1.3 V ± 50 mV	V
DDR DRAM I/O voltage	GV_{DD}	2.5 V ± 125 mV	V
Three-speed Ethernet I/O voltage	LV_{DD}	3.3 V ± 165 mV 2.5 V ± 125 mV	V
PCI/PCI-X, local bus, RapidIO, 10/100 Ethernet, MII management, DUART, system control and power management, I^2C, and JTAG I/O voltage	OV_{DD}	3.3 V ± 165 mV	V

Table 2. Recommended Operating Conditions (continued)

Characteristic		Symbol	Recommended Value	Unit
Input voltage	DDR DRAM signals	MV_{IN}	GND to GV_{DD}	V
	DDR DRAM reference	MV_{REF}	GND to $GV_{DD/2}$	V
	Three-speed Ethernet signals	LV_{IN}	GND to LV_{DD}	V
	PCI/PCI-X, local bus, RapidIO, 10/100 Ethernet, MII management, DUART, SYSCLK, system control and power management, I^2C, and JTAG signals	OV_{IN}	GND to OV_{DD}	V
Die-junction temperature		T_j	0 to 105	•C

Figure 2 shows the undershoot and overshoot voltages at the interfaces of the MPC8540.



Note:
t_{SYS} refers to the clock period associated with the SYSCLK signal.

Figure 2. Overshoot/Undershoot Voltage for $GV_{DD}/OV_{DD}/LV_{DD}$

The MPC8540 core voltage must always be provided at nominal 1.2 V (see Table 2 for actual recommended core voltage). Voltage to the processor interface I/Os are provided through separate sets of supply pins and must be provided at the voltages shown in Table 2. The input voltage threshold scales with respect to the associated I/O supply voltage. OV_{DD} and LV_{DD} based receivers are simple CMOS I/O circuits and satisfy appropriate LVCMOS type specifications. The DDR SDRAM interface uses a single-ended differential receiver referenced the externally supplied MV_{REF} signal (nominally set to $GV_{DD}/2$) as is appropriate for the SSTL2 electrical signaling standard.

Figure 3 shows the undershoot and overshoot voltage of the PCI interface of the MPC8540 for the 3.3-V signals, respectively.

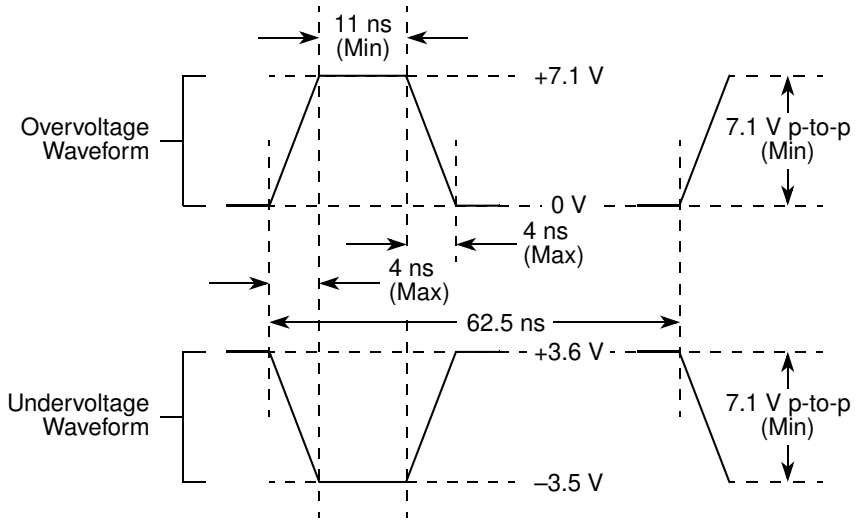


Figure 3. Maximum AC Waveforms on PCI interface for 3.3-V Signaling

2.1.4 Output Driver Characteristics

Table 3 provides information on the characteristics of the output driver strengths. The values are preliminary estimates.

Table 3. Output Drive Capability

Driver Type	Programmable Output Impedance (Ω)	Supply Voltage	Notes
Local bus interface utilities signals	25	OV_{DD} = 3.3 V	1
	42 (default)		
PCI signals	25		2
	42 (default)		
DDR signal	20	GV_{DD} = 2.5 V	
TSEC/10/100 signals	42	LV_{DD} = 2.5/3.3 V	
DUART, system control, I2C, JTAG	42	OV_{DD} = 3.3 V	
RapidIO N/A (LVDS signaling)	N/A		

Notes:

1. The drive strength of the local bus interface is determined by the configuration of the appropriate bits in PORIMPSCR.
2. The drive strength of the PCI interface is determined by the setting of the $\overline{\text{PCI\_GNT1}}$ signal at reset.

3 Power Characteristics

The estimated power dissipation on the V_{DD} supply for the MPC8540 is shown in Table 4.

Table 4. MPC8540 V_{DD} Power Dissipation [1,2]

CCB Frequency (MHz)	Core Frequency (MHz)	Typical Power[3,4]	Maximum Power[5]	Unit
200	400	4.6	7.2	W
	500	4.9	7.5	
	600	5.3	7.9	
267	533	5.5	8.2	W
	667	5.9	8.7	
	800	6.4	10.2	
333	667	6.3	9.3	W
	833	6.9	10.9	
	1000 [6]	11.3	15.9	

Notes:

1. The values do not include I/O supply power (OV_{DD}, LV_{DD}, GV_{DD}) or AV_{DD}.
2. Junction temperature is a function of die size, on-chip power dissipation, package thermal resistance, mounting site (board) temperature, air flow, power dissipation of other components on the board, and board thermal resistance. Any customer design must take these considerations into account to ensure the maximum 105 °C junction temperature is not exceeded on this device.
3. Typical Power is based on a nominal voltage of V_{DD} = 1.2 V, a nominal process, a junction temperature of T_j = 105 °C, and a Dhrystone 2.1 benchmark application.
4. Thermal solutions will likely need to design to a number higher than Typical Power based on the end application, T_A target, and I/O power.
5. Maximum power is based on a nominal voltage of V_{DD} = 1.2 V, worst case process, a junction temperature of T_j = 105 °C, and an artificial smoke test.
6. The nominal recommended V_{DD} is 1.3 V for this speed grade.

The estimated power dissipation on the AV_{DD} supplies for the MPC8540 PLLs is shown in Table 5.

Table 5. MPC8540 AV_{DD} Power Dissipation

$AV_{DD}n$	Typical[1]	Unit
$AV_{DD}1$	0.007	W
$AV_{DD}2$	0.014	W

Notes:

1. V_{DD} = 1.2 V (1.3 V for 1.0 GHz device), T_J = 105°C

Table 6 provides estimated I/O power numbers for each block: DDR, PCI, Local Bus, RapidIO, TSEC, and FEC.

Table 6. Estimated Typical I/O Power Consumption

Interface	Parameter	GV_{DD} (2.5 V)	OV_{DD} (3.3 V)	LV_{DD} (3.3 V)	LV_{DD} (2.5 V)	Units	Notes
DDR I/O	CCB = 200 MHz	0.46				W	1
	CCB = 266 MHz	0.59					
	CCB = 300 MHz	0.66					
	CCB = 333 MHz	0.73					
PCI/PCI-X I/O	32-bit, 33 MHz		0.04			W	2
	32-bit 66 MHz		0.07				
	64-bit, 66 MHz		0.14				
	64-bit, 133 MHz		0.25				
Local Bus I/O	32-bit, 33 MHz		0.07			W	3
	32-bit, 66 MHz		0.13				
	32-bit, 133 MHz		0.24				
	32-bit, 167 MHz		0.30				
RapidIO I/O	500 MHz data rate		0.96			W	4
TSEC I/O	MII			10		mW	5, 6
	GMII, TBI (2.5 V)				40		
	GMII, TBI (3.3 V)			70			
	RGMII, RTBI				40		
FEC I/O	MII		10			mW	7

Notes:

1. GV_{DD}=2.5, ECC enabled, 66% bus utilization, 33% write cycles, 10pF load on data, 10pF load on address/command, 10pF load on clock
2. OV_{DD}=3.3, 30pF load per pin, 54% bus utilization, 33% write cycles
3. OV_{DD}=3.3, 25pF load per pin, 5pF load on clock, 40% bus utilization, 33% write cycles
4. V_{DD}=1.2, OV_{DD}=3.3
5. LVDD=2.5/3.3, 15pF load per pin, 25% bus utilization
6. Power dissipation for one TSEC only
7. OV_{DD}=3.3, 20pF load per pin, 25% bus utilization

4 Clock Timing

4.1 System Clock Timing

Table 7 provides the system clock (SYSCLK) AC timing specifications for the MPC8540.

Table 7. SYSCLK AC Timing Specifications

Parameter/Condition	Symbol	Min	Typical	Max	Unit	Notes
SYSCLK frequency	f_{SYSCLK}	—	—	166	MHz	1
SYSCLK cycle time	t_{SYSCLK}	6.0	—	—	ns	
SYSCLK rise and fall time	t_{KH}, t_{KL}	0.6	1.0	1.2	ns	2
SYSCLK duty cycle	t_{KHKL}/t_{SYSCLK}	40	—	60	%	3
SYSCLK jitter	—	—	—	+/- 150	ps	4, 5

Notes:

1. **Caution:** The CCB to SYSCLK ratio and e500 core to CCB ratio settings must be chosen such that the resulting SYSCLK frequency, e500 (core) frequency, and CCB frequency do not exceed their respective maximum or minimum operating frequencies. Refer to Section 15.2, "Platform/System PLL Ratio," and Section 15.3, "e500 Core PLL Ratio," for ratio settings.
2. Rise and fall times for SYSCLK are measured at 0.6 V and 2.7 V.
3. Timing is guaranteed by design and characterization.
4. This represents the total input jitter—short term and long term—and is guaranteed by design.
5. For spread spectrum clocking, guidelines are +/-1% of the input frequency with a maximum of 60 kHz of modulation regardless of the input frequency.

4.2 TSEC Gigabit Reference Clock Timing

Table 7 provides the TSEC gigabit reference clock (EC_GTX_CLK125) AC timing specifications for the MPC8540.

Table 8. EC_GTX_CLK125 AC Timing Specifications

Parameter/Condition	Symbol	Min	Typical	Max	Unit	Notes
EC_GTX_CLK125 frequency	f_{G125}	—	125	—	MHz	
EC_GTX_CLK125 cycle time	t_{G125}	—	8	—	ns	
EC_GTX_CLK125 rise and fall time LV_{DD}=2.5 LV_{DD}=3.3	t_{G125R}, t_{G125F}	—	—	 0.75 1	ns	2
EC_GTX_CLK125 duty cycle GMII, TBI RGMII, RTBI	t_{G125H}/t_{G125}	 45 47	—	 55 53	%	1,3

Notes:

1. Timing is guaranteed by design and characterization.
2. Rise and fall times for EC_GTX_CLK125 are measured from 0.5V and 2.0V for LV_{DD}=2.5V, and from 0.6 and 2.7V for LV_{DD}=3.3V.
3. EC_GTX_CLK125 is used to generate GTX clock for TSEC transmitter with 2% degradation EC_GTX_CLK125 duty cycle can be loosened from 47/53% as long as PHY device can tolerate the duty cycle generated by GTX_CLK of TSEC.

4.3 RapidIO Transmit Clock Input Timing

Table 9 provides the RapidIO transmit clock input (RIO_TX_CLK_IN) AC timing specifications for the MPC8540.

Table 9. RIO_TX_CLK_IN AC Timing Specifications

Parameter/Condition	Symbol	Min	Typical	Max	Unit	Notes
RIO_TX_CLK_IN frequency	f_{RCLK}	125	—	—	MHz	
RIO_TX_CLK_IN cycle time	t_{RCLK}	—	—	8	ns	
RIO_TX_CLK_IN duty cycle	t_{RCLKH}/t_{RCLK}	48	—	52	%	1

Notes:

1. Requires ±100 ppm long term frequency stability. Timing is guaranteed by design and characterization.

4.4 Real Time Clock Timing

Table 10 provides the real time clock (RTC) AC timing specifications for the MPC8540.

Table 10. RTC AC Timing Specifications

Parameter/Condition	Symbol	Min	Typical	Max	Unit	Notes
RTC clock high time	t_{RTCH}	2 x t_{CCB_CLK}	—	—	ns	
RTC clock low time	t_{RTCL}	2 x t_{CCB_CLK}	—	—	ns	

5 RESET Initialization

This section describes the AC electrical specifications for the RESET initialization timing requirements of the MPC8540. Table 7 provides the RESET initialization AC timing specifications for the MPC8540.

Table 11. RESET Initialization Timing Specifications

Parameter/Condition	Min	Max	Unit	Notes
Required assertion time of $\overline{\text{HRESET}}$	100	—	μs	
Minimum assertion time for $\overline{\text{SRESET}}$	512	—	SYSCLKs	1
PLL input setup time with stable SYSCLK before $\overline{\text{HRESET}}$ negation	100	—	μs	
Input setup time for POR configs (other than PLL config) with respect to negation of $\overline{\text{HRESET}}$	4	—	SYSCLKs	1
Input hold time for POR configs (including PLL config) with respect to negation of $\overline{\text{HRESET}}$	2	—	SYSCLKs	1

Table 11. RESET Initialization Timing Specifications (continued)

Parameter/Condition	Min	Max	Unit	Notes
Maximum valid-to-high impedance time for actively driven POR configs with respect to negation of $\overline{\text{HRESET}}$	—	5	SYSCLKs	1

Notes:
1.SYSCLK is identical to the PCI_CLK signal and is the primary clock input for the MPC8540. See the MPC8540 Integrated Processor Preliminary Reference Manual for more details.

Table 12 provides the PLL and DLL lock times.

Table 12. PLL and DLL Lock Times

Parameter/Condition	Min	Max	Unit	Notes
PLL lock times	—	100	μs	
DLL lock times	7680	122,880	CCB Clocks	1, 2

Notes:
1.DLL lock times are a function of the ratio between the output clock and the platform (or CCB) clock. A 2:1 ratio results in the minimum and an 8:1 ratio results in the maximum.
2. The CCB clock is determined by the SYSCLK × platform PLL ratio.

6 DDR SDRAM

This section describes the DC and AC electrical specifications for the DDR SDRAM interface of the MPC8540.

6.1 DDR SDRAM DC Electrical Characteristics

Table 13 provides the recommended operating conditions for the DDR SDRAM component(s) of the MPC8540.

Table 13. DDR SDRAM DC Electrical Characteristics

Parameter/Condition	Symbol	Min	Max	Unit	Notes
I/O supply voltage	GV_{DD}	2.375	2.625	V	1
I/O reference voltage	MV_{REF}	$0.49 \times GV_{DD}$	$0.51 \times GV_{DD}$	V	2
I/O termination voltage	V_{TT}	$MV_{REF} - 0.04$	$MV_{REF} + 0.04$	V	3
Input high voltage	V_{IH}	$MV_{REF} + 0.18$	$GV_{DD} + 0.3$	V	4
Input low voltage	V_{IL}	–0.3	$MV_{REF} - 0.18$	V	4
Output leakage current	I_{OZ}	–10	10	μA	5
Output high current (V_{OUT} = 1.95 V)	I_{OH}	–15.2	—	mA	
Output low current (V_{OUT} = 0.35 V)	I_{OL}	15.2	—	mA	

Table 13. DDR SDRAM DC Electrical Characteristics (continued)

Parameter/Condition	Symbol	Min	Max	Unit	Notes
MV_{REF} input leakage current	I_{VREF}	—	100	μA	

Notes:

1. GV_{DD} is expected to be within 50 mV of the DRAM GV_{DD} at all times.
2. MV_{REF} is expected to be equal to 0.5 × GV_{DD}, and to track GV_{DD} DC variations as measured at the receiver. Peak-to-peak noise on MV_{REF} may not exceed ±2% of the DC value.
3. V_{TT} is not applied directly to the device. It is the supply to which far end signal termination is made and is expected to be equal to MV_{REF}. This rail should track variations in the DC level of MV_{REF}.
4. V_{IH} can tolerate an overshoot of 1.2V over GV_{DD} for a pulse width of ≤3 ns, and the pulse width cannot be greater than t_{MCK}. V_{IL} can tolerate an undershoot of 1.2V below GND for a pulse width of ≤3 ns, and the pulse width cannot be greater than t_{MCK}.
5. Output leakage is measured with all outputs disabled, 0 V ≤ V_{OUT} ≤ GV_{DD}.

Table 14 provides the DDR capacitance.

Table 14. DDR SDRAM Capacitance

Parameter/Condition	Symbol	Min	Max	Unit	Notes
Input/output capacitance: DQ, DQS, MSYNC_IN	C_{IO}	6	8	pF	1
Delta input/output capacitance: DQ, DQS	C_{DIO}	—	0.5	pF	1

Note:

1. This parameter is sampled. GV_{DD} = 2.5 V ± 0.125 V, f = 1 MHz, T_A = 25°C, V_{OUT} = GV_{DD}/2, V_{OUT} (peak to peak) = 0.2 V.

6.2 DDR SDRAM AC Electrical Characteristics

This section provides the AC electrical characteristics for the DDR SDRAM interface.

6.2.1 DDR SDRAM Input AC Timing Specifications

Table 15 provides the input AC timing specifications for the DDR SDRAM interface.

Table 15. DDR SDRAM Input AC Timing Specifications

At recommended operating conditions with GV_{DD} of 2.5 V ± 5%.

Parameter	Symbol	Min	Max	Unit	Notes
AC input low voltage	V_{IL}	—	MV_{REF} – 0.31	V	
AC input high voltage	V_{IH}	MV_{REF} + 0.31	GV_{DD} + 0.3	V	
MDQS—MDQ/MECC input skew per byte For DDR = 333 MHz For DDR ≤ 266 MHz	t_{DISKEW}	 -750 -1125	 750 1125	ps	1, 2

Note:

1. Maximum possible skew between a data strobe (MDQS[n]) and any corresponding bit of data (MDQ[8n + {0...7}] if 0 ≤ n ≤ 7) or ECC (MECC[{0...7}] if n=8).
2. For timing budget analysis, the MPC8540 consumes ±550 ps of the total budget.

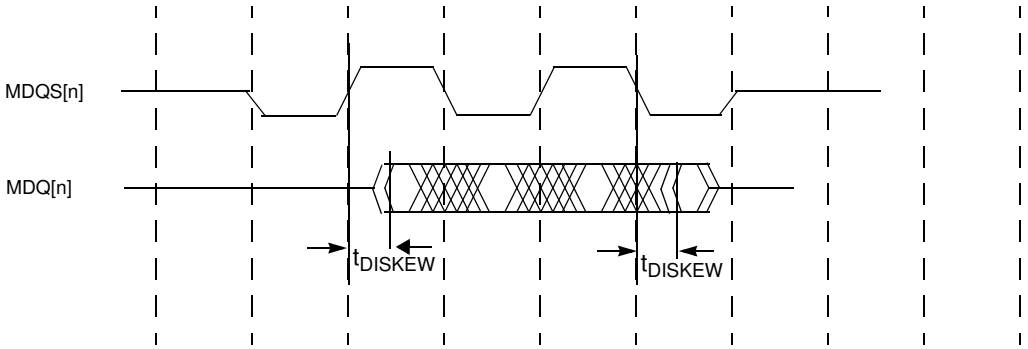


Figure 4. DDR SDRAM Interface Input Timing

6.2.2 DDR SDRAM Output AC Timing Specifications

For chip selects $\overline{\text{MCS1}}$ and $\overline{\text{MCS2}}$, there will always be at least 200 DDR memory clocks coming out of self-refresh after an $\overline{\text{HRESET}}$ before a precharge occurs. This will not necessarily be the case for chip selects $\overline{\text{MCS0}}$ and $\overline{\text{MCS3}}$.

6.2.2.1 DLL Enabled Mode

Table 16 and Table 17 provide the output AC timing specifications and measurement conditions for the DDR SDRAM interface with the DDR DLL enabled.

Table 16. DDR SDRAM Output AC Timing Specifications–DLL Mode

At recommended operating conditions with GV_{DD} of 2.5 V ± 5%.

Parameter	Symbol [1]	Min	Max	Unit	Notes
MCK[n] cycle time, (MCK[n]/$\overline{\text{MCK}}$[n] crossing)	t_{MCK}	6	10	ns	2
On chip Clock Skew	$t_{MCKSKEW}$	—	150	ps	3, 8
MCK[n] duty cycle	t_{MCKH}/t_{MCK}	45	55	%	8
ADDR/CMD output valid	t_{DDKHOV}	—	3	ns	4, 9
ADDR/CMD output invalid	t_{DDKHOX}	1	—	ns	4, 9
Write CMD to first MDQS capture edge	t_{DDSHMH}	t_{MCK} + 1.5	t_{MCK} + 4.0	ns	5
MDQ/MECC/MDM output setup with respect to MDQS 333 MHz 266 MHz 200 MHz	t_{DDKHDS}, t_{DDKLDS}	 900 1100 1200	—	ps	6, 9
MDQ/MECC/MDM output hold with respect to MDQS 333 MHz 266 MHz 200 MHz	t_{DDKHDX}, t_{DDKLDX}	 900 1100 1200	—	ps	6, 9
MDQS preamble start	t_{DDSHMP}	0.75 × t_{MCK} + 1.5	0.75 × t_{MCK} + 4.0	ns	7, 8

Table 16. DDR SDRAM Output AC Timing Specifications–DLL Mode (continued)

At recommended operating conditions with GV_{DD} of 2.5 V ± 5%.

Parameter	Symbol [1]	Min	Max	Unit	Notes
MDQS epilogue end	t_{DDSHME}	1.5	4.0	ns	7, 8

Notes:

1.The symbols used for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state) (reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. Output hold time can be read as DDR timing (DD) from the rising or falling edge of the reference clock (KH or KL) until the output went invalid (OX or DX). For example, t_{DDKHOV} symbolizes DDR timing (DD) for the time t_{MCK} memory clock reference (K) goes from the high (H) state until outputs (O) are valid (V) or output valid time. Also, t_{DDKLDX} symbolizes DDR timing (DD) for the time t_{MCK} memory clock reference (K) goes low (L) until data outputs (D) are invalid (X) or data output hold time.

2.All MCK/$\overline{\text{MCK}}$ referenced measurements are made from the crossing of the two signals ±0.1 V.

3.Maximum possible clock skew between a clock MCK[n] and its relative inverse clock $\overline{\text{MCK}}$[n], or between a clock MCK[n] and a relative clock MCK[m] or MSYNC_OUT. Skew measured between complementary signals at $GV_{DD}/2$.

4.ADDR/CMD includes all DDR SDRAM output signals except MCK/$\overline{\text{MCK}}$ and MDQ/MECC/MDM/MDQS.

5.Note that t_{DDSHMH} follows the symbol conventions described in note 1. For example, t_{DDSHMH} describes the DDR timing (DD) from the rising edge of the MSYNC_IN clock (SH) until the MDQS signal is valid (MH). t_{DDSHMH} can be modified through control of the DQSS override bits in the TIMING_CFG_2 register. These controls allow the relationship between the synchronous clock control timing and the source-synchronous DQS domain to be modified by the user. For best turnaround times, these may need to be set to delay t_{DDSHMH} an additional $0.25t_{MCK}$. This will also affect t_{DDSHMP} and t_{DDSHME} accordingly. See the *MPC8540 PowerQUICC III Integrated Host Processor Reference Manual* for a description and understanding of the timing modifications enabled by use of these bits.

6.Determined by maximum possible skew between a data strobe (MDQS) and any corresponding bit of data (MDQ), ECC (MECC), or data mask (MDM). The data strobe should be centered inside of the data eye at the pins of the MPC8540.

7.All outputs are referenced to the rising edge of MSYNC_IN (S) at the pins of the MPC8540. Note that t_{DDSHMP} follows the symbol conventions described in note 1. For example, t_{DDSHMP} describes the DDR timing (DD) from the rising edge of the MSYNC_IN clock (SH) for the duration of the MDQS signal precharge period (MP).

8.Guaranteed by design.

9.Guaranteed by characterization.

Figure 5 provides the AC test load for the DDR bus.

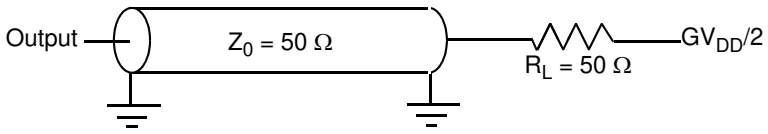


Figure 5. DDR AC Test Load

Table 17. DDR SDRAM Measurement Conditions

Symbol	DDR	Unit	Notes
V_{TH}	MV_{REF} ± 0.31 V	V	1
V_{OUT}	0.5 × GV_{DD}	V	2

Notes:

1.Data input threshold measurement point.

2.Data output measurement point.

Figure 6 shows the DDR SDRAM output timing diagram.

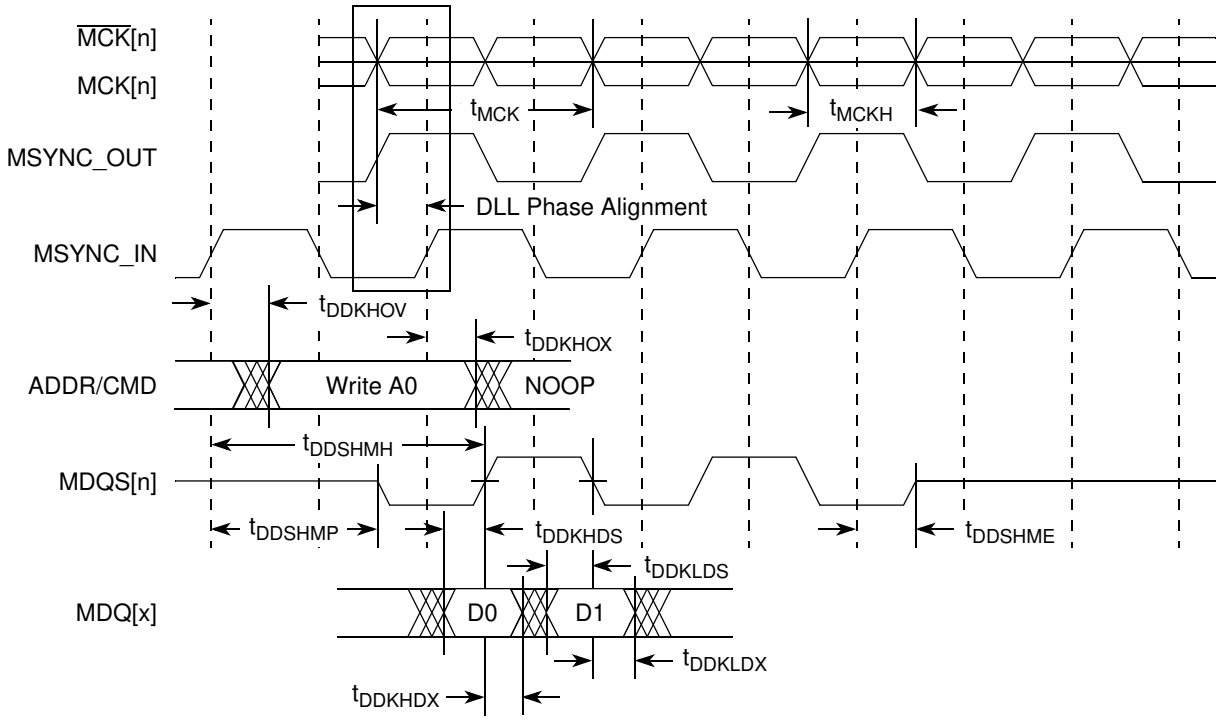


Figure 6. DDR SDRAM Output Timing Diagram

6.2.2.2 Load Effects on Address/Command Bus

Table 18 provides approximate delay information that can be expected for the address and command signals of the DDR controller for various loadings. These numbers are the result of simulations for one topology. The delay numbers will strongly depend on the topology used. These delay numbers show the total delay for the address and command to arrive at the DRAM devices. The actual delay could be different than the delays seen in simulation, depending on the system topology. If a heavily loaded system is used, the DLL loop may need to be adjusted to meet setup requirements at the DRAM.

Table 18. Expected Delays for Address/Command

Load	Delay	Unit
4 devices (12 pF)	3.0	ns
9 devices (27 pF)	3.6	ns
36 devices (108 pF) + 40 pF compensation capacitor	5.0	ns
36 devices (108 pF) + 80 pF compensation capacitor	5.2	ns

7 DUART

This section describes the DC and AC electrical specifications for the DUART interface of the MPC8540.

7.1 DUART DC Electrical Characteristics

Table 19 provides the DC electrical characteristics for the DUART interface of the MPC8540.

Table 19. DUART DC Electrical Characteristics

Parameter	Symbol	Min	Max	Unit
High-level input voltage	V_{IH}	2	OV_{DD} + 0.3	V
Low-level input voltage	V_{IL}	–0.3	0.8	V
Input current (V_{IN} [1] = 0 V or V_{IN} = V_{DD})	I_{IN}	—	±5	μA
High-level output voltage (OV_{DD} = min, I_{OH} = –100 μA)	V_{OH}	OV_{DD} – 0.2	—	V
Low-level output voltage (OV_{DD} = min, I_{OL} = 100 μA)	V_{OL}	—	0.2	V

Note:

1.Note that the symbol V_{IN}, in this case, represents the OV_{IN} symbol referenced in Table 1 and Table 2.

7.2 DUART AC Electrical Specifications

Table 20 provides the AC timing parameters for the DUART interface of the MPC8540.

Table 20. DUART AC Timing Specifications

Parameter	Value	Unit	Notes
Minimum baud rate	f_{CCB_CLK} / 1048576	baud	3
Maximum baud rate	f_{CCB_CLK} / 16	baud	1, 3
Oversample rate	16	—	2, 3

Notes:

1.Actual attainable baud rate will be limited by the latency of interrupt processing.

2.The middle of a start bit is detected as the 8^{th} sampled 0 after the 1-to-0 transition of the start bit. Subsequent bit values are sampled each 16^{th} sample.

3.Guaranteed by design.

8 Ethernet: Three-Speed,10/100, MII Management

This section provides the AC and DC electrical characteristics for three-speed, 10/100, and MII management.

8.1 Three-Speed Ethernet Controller (TSEC) (10/100/1Gb Mbps)—GMII/MII/TBI/RGMII/RTBI Electrical Characteristics

The electrical characteristics specified here apply to all GMII (gigabit media independent interface), MII (media independent interface), TBI (ten-bit interface), RGMII (reduced gigabit media independent interface), and RTBI (reduced ten-bit interface) signals except MDIO (management data input/output) and MDC (management data clock). The RGMII and RTBI interfaces are defined for 2.5 V, while the GMII, MII, and TBI interfaces can be operated at 3.3 or 2.5 V. Whether the GMII, MII, or TBI interface is operated at 3.3 or 2.5 V, the timing is compliant with the IEEE 802.3 standard. The RGMII and RTBI interfaces follow the Hewlett-Packard reduced pin-count interface for Gigabit Ethernet Physical Layer Device Specification Version 1.2a (9/22/2000). The electrical characteristics for MDIO and MDC are specified in Section 8.4, "Ethernet Management Interface Electrical Characteristics."

8.1.1 TSEC DC Electrical Characteristics

All GMII, MII, TBI, RGMII, and RTBI drivers and receivers comply with the DC parametric attributes specified in Table 21 and Table 22. The potential applied to the input of a GMII, MII, TBI, RGMII, or RTBI receiver may exceed the potential of the receiver's power supply (i.e., a GMII driver powered from a 3.6 V supply driving V_{OH} into a GMII receiver powered from a 2.5 V supply). Tolerance for dissimilar GMII driver and receiver supply potentials is implicit in these specifications. The RGMII and RTBI signals are based on a 2.5 V CMOS interface voltage as defined by JEDEC EIA/JESD8-5.

Table 21. GMII, MII, and TBI DC Electrical Characteristics

Parameter	Symbol	Min	Max	Unit
Supply voltage 3.3 V	LV_{DD}	3.13	3.47	V
Output high voltage (LV_{DD} = Min, I_{OH} = –4.0 mA)	V_{OH}	2.40	LV_{DD} + 0.3	V
Output low voltage (LV_{DD} = Min, I_{OL} = 4.0 mA)	V_{OL}	GND	0.50	V
Input high voltage	V_{IH}	1.70	LV_{DD} + 0.3	V
Input low voltage	V_{IL}	–0.3	0.90	V
Input high current (V_{IN} [1] = LV_{DD})	I_{IH}	—	40	μA
Input low current (V_{IN} [1] = GND)	I_{IL}	–600	—	μA

Note:

1.The symbol V_{IN}, in this case, represents the LV_{IN} symbol referenced in Table 1 and Table 2.

Table 22. GMII, MII, RGMII, RTBI, and TBI DC Electrical Characteristics

Parameters	Symbol	Min	Max	Unit
Supply voltage 2.5 V	LV_{DD}	2.37	2.63	V
Output high voltage (LV_{DD} = Min, I_{OH} = –1.0 mA)	V_{OH}	2.00	LV_{DD} + 0.3	V
Output low voltage (LV_{DD} = Min, I_{OL} = 1.0 mA)	V_{OL}	GND – 0.3	0.40	V
Input high voltage	V_{IH}	1.70	LV_{DD} + 0.3	V
Input low voltage	V_{IL}	–0.3	0.70	V
Input high current (V_{IN} [1] = LV_{DD})	I_{IH}	—	10	μA
Input low current (V_{IN} [1] = GND)	I_{IL}	–15	—	μA

Note:
1.Note that the symbol V_{IN}, in this case, represents the LV_{IN} symbol referenced in Table 1and Table 2.

8.2 GMII, MII, TBI, RGMII, and RTBI AC Timing Specifications

The AC timing specifications for GMII, MII, TBI, RGMII, and RTBI are presented in this section.

8.2.1 GMII AC Timing Specifications

This section describes the GMII transmit and receive AC timing specifications.

8.2.1.1 GMII Transmit AC Timing Specifications

Table 23 provides the GMII transmit AC timing specifications.

Table 23. GMII Transmit AC Timing Specifications

At recommended operating conditions with LV_{DD} of 3.3 V ± 5%, or LV_{DD}=2.5V ± 5%.

Parameter/Condition	Symbol [1]	Min	Typ	Max	Unit
GTX_CLK clock period	t_{GTX}	—	8.0	—	ns
GTX_CLK duty cycle	t_{GTXH}/t_{GTX}	40	—	60	%
GMII data TXD[7:0], TX_ER, TX_EN setup time	t_{GTKHDV}	2.5	—	—	ns
GTX_CLK to GMII data TXD[7:0], TX_ER, TX_EN delay	t_{GTKHDX} [3]	0.5	—	5.0	ns

Table 23. GMII Transmit AC Timing Specifications (continued)

At recommended operating conditions with LV_{DD} of 3.3 V ± 5%, or LV_{DD}=2.5V ± 5%.

Parameter/Condition	Symbol [1]	Min	Typ	Max	Unit
GTX_CLK data clock rise and fall time	t_{GTXR}, t_{GTXF} [2,4]	—	—	1.0	ns

Notes:

1. The symbols used for timing specifications herein follow the pattern $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{GTKHDV} symbolizes GMII transmit timing (GT) with respect to the t_{GTX} clock reference (K) going to the high state (H) relative to the time date input signals (D) reaching the valid state (V) to state or setup time. Also, t_{GTKHDX} symbolizes GMII transmit timing (GT) with respect to the t_{GTX} clock reference (K) going to the high state (H) relative to the time date input signals (D) going invalid (X) or hold time. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For example, the subscript of t_{GTX} represents the GMII(G) transmit (TX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
2. Signal timings are measured at 0.7 V and 1.9 V voltage levels.
3. Guaranteed by characterization.
4. Guaranteed by design.

Figure 7 shows the GMII transmit AC timing diagram.

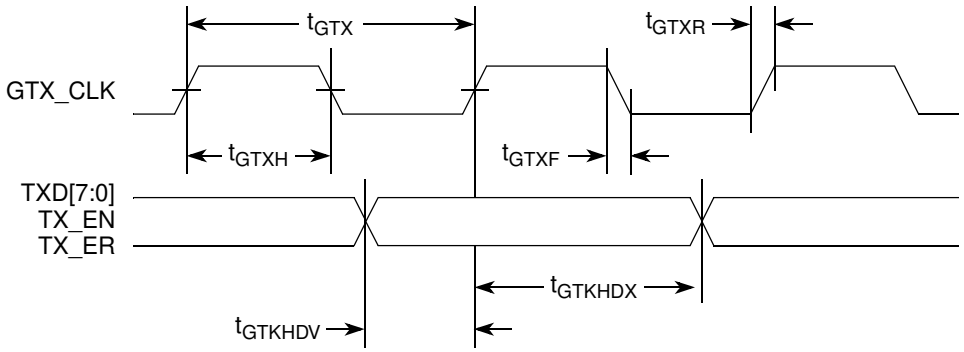


Figure 7. GMII Transmit AC Timing Diagram

8.2.1.2 GMII Receive AC Timing Specifications

Table 24 provides the GMII receive AC timing specifications.

Table 24. GMII Receive AC Timing Specifications

At recommended operating conditions with LV_{DD} of 3.3 V ± 5%, or LV_{DD}=2.5V ± 5%.

Parameter/Condition	Symbol [1]	Min	Typ	Max	Unit
RX_CLK clock period	t_{GRX}	—	8.0	—	ns
RX_CLK duty cycle	t_{GRXH}/t_{GRX}	40	—	60	ns
RXD[7:0], RX_DV, RX_ER setup time to RX_CLK	t_{GRDVKH}	2.0	—	—	ns
RXD[7:0], RX_DV, RX_ER hold time to RX_CLK	t_{GRDXKH}	0.5	—	—	ns

Table 24. GMII Receive AC Timing Specifications (continued)

At recommended operating conditions with LV_{DD} of 3.3 V ± 5%, or LV_{DD}=2.5V ± 5%.

Parameter/Condition	Symbol [1]	Min	Typ	Max	Unit
RX_CLK clock rise and fall time	t_{GRXR}, t_{GRXF} [2,3]	—	—	1.0	ns

Note:

1. The symbols used for timing specifications herein follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{GRDVKH} symbolizes GMII receive timing (GR) with respect to the time data input signals (D) reaching the valid state (V) relative to the t_{RX} clock reference (K) going to the high state (H) or setup time. Also, t_{GRDXKL} symbolizes GMII receive timing (GR) with respect to the time data input signals (D) went invalid (X) relative to the t_{GRX} clock reference (K) going to the low (L) state or hold time. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For example, the subscript of t_{GRX} represents the GMII (G) receive (RX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
2. Signal timings are measured at 0.7 V and 1.9 V voltage levels.
3. Guaranteed by design.

Figure 8 provides the AC test load for TSEC.

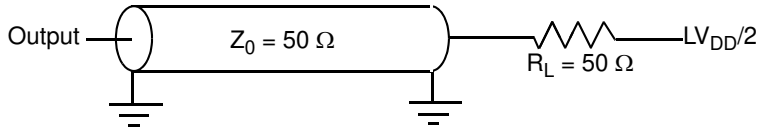


Figure 8. TSEC AC Test Load

Figure 9 shows the GMII receive AC timing diagram.

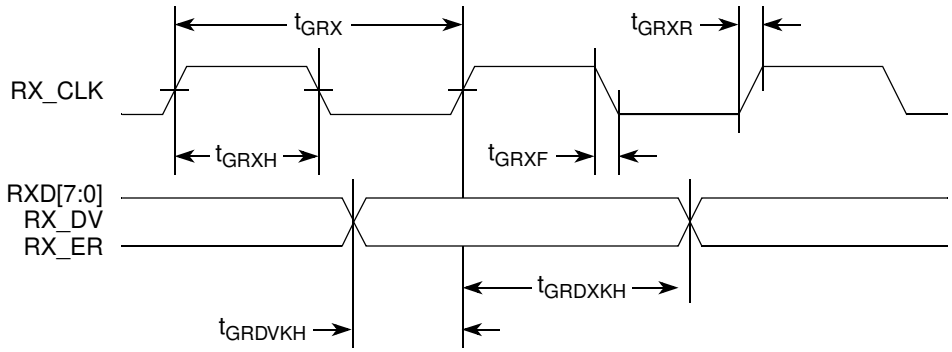


Figure 9. GMII Receive AC Timing Diagram